

## Using Fault Tree Analysis in Complex Systems

- Berquó, Jolan Eduardo – Electronic Eng. (ITA)
- Aerospace Product Certifier (DCTA/IFI)
- Government Representative for Quality Assurance – RGQ (DCTA/IFI)
- Post-graduated in Reliability Engineering and System Safety Engineering (ITA)
- Specialization in Systems Engineering and Analysis (Italy)
- Participation in the joint development program (Brazil-Italy) for the AM-X military fighter-bomber aircraft
- Experience of one decade as an engineer responsible for off-line maintenance of electronic systems and aircraft instruments.

[jberquo@dcabr.org.br](mailto:jberquo@dcabr.org.br) / [jberquo@gmail.com](mailto:jberquo@gmail.com)

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In the last paragraph of MSC 72, we have said that the minimum cut sets (CCM's) technique is also used in the Fault Tree Analysis (FTA) tool. In fact, when we are faced with complex systems with units having various failure modes, it is difficult to use the Reliability Blocks Diagrams (RBD), so it is more prudent to adopt the CCM's technique in the FTA, or in Success Tree Analysis (STA). In addition, these two tools allow us to also include the role of the human being in the system.

From our already somewhat exhaustive considerations in previous MSCs, we know that the Fault Tree Analysis or Assessment (FTA) is a deductive analysis, that is, an undesirable event is postulated for a system, called the Top Event, deducing the possible causes of this event. It is often said that it is the method of detectives, which start from an unwanted result (homicide, for example) and search for killers (causes)

Well, let's treat FTA in this MSC using the Cut Sets methodology presented in MSC 72. Let's start with the block diagram below that was treated in Fig.1 of MSC 72. It is a simple block diagram series-parallel.

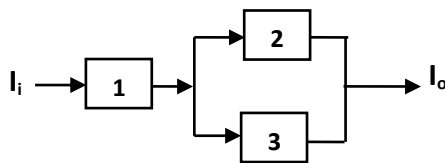


Fig. 1 – Example of a single diagram series-parallel

The current  $I_i$  is supplied to the unit 1, which processes it and forwards it to the two identical units 2 and 3.

We have the following set of cut sets:  $C_1 = \{1\}$  and  $C_2 = \{2, 3\}$ . As we know, a cut set is a set of units of the system under analysis that, if they fail, cause the system to fail as a whole.

The FTA for the system, considering its cut sets, is shown in Fig. 2.

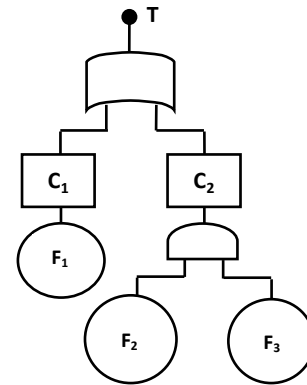


Fig. 2 – FTA of the system in Fig. 1

Notice that we have an "Or" gate, from which emerges the top event  $T$ , with the inputs  $C_1$ , which corresponds to the failure  $F_1$  of unit 1, and the input  $C_2$ , which emerges from the "And" gate, whose inputs correspond to the failures  $F_1$  and  $F_2$  of units 2 and 3.

According to Boolean Algebra:

$$T = C_1 \cup C_2$$

$$C_1 = F_1$$

$C_2 = F_2 \cdot F_3$ . On the other hand, as we saw in MSC 72, we can write::

$$Pr(T) = Pr(C_1 \cup C_2) = Pr(C_1) + Pr(C_2), \quad (1)$$

Just because  $C_1$  and  $C_2$  are disjoint, i.e., they have no common units..

If  $Pr(T)$  is the fallibility (or unreliability)  $F_s$  of the system, which is given by  $F = \lambda t$ , when  $t$  is small, which occurs if we admit, for example,  $t = 1h$ . In this way, we can write:

$$F_s = \lambda_1 \cdot \lambda_2 + \lambda_3 \text{ with } t=1h$$

Let us assume that  $\lambda_1 = 10^{-3}$  and  $\lambda_2 = \lambda_3 = 2 \times 10^{-3}$ . It follows that

$$F_s = 10^{-3} + (2 \times 10^{-3}) \cdot (2 \times 10^{-3}).$$

$$F_s = 10^{-3} + (2 \times 10^{-3}) \cdot (2 \times 10^{-3}) = 0,005.$$

Since  $R_S = 1 - F_S$ , it turns out that  $R_S = 1 - 0.005 = 0.995$ .  
Now, let us consider the system of the Fig. 3.

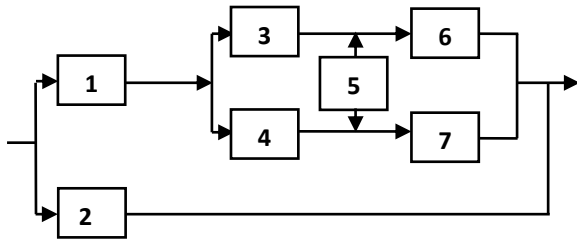


Fig. 3 – Example of Complex System

It is a complex system. We will solve it also by means of an FTA, considering the minimum cut sets (CCM's). A CCM is the smallest set of units to ensure an interruption of the flow to the output. As we saw in MSC 72, the CCM's of the above system are the sets: (1, 2), (3, 4, 2) and (6, 7, 2).

The FTA for the system is shown in Fig.4.

Note that the CCM's are not disjoint because the unit 2 is in all of them. In this way, we must rigorously write:

$$F_S = \Pr(T) = \Pr(C_1 \cup C_2 \cup C_3) - \Pr(C_1 \cap C_2 \cap C_3) =$$

$$\Pr(C_1) + \Pr(C_2) + \Pr(C_3) - \Pr(C_1.C_2.C_3) \quad (2)$$

$$\text{We have: } C_1 = F_1.F_2; C_2 = F_3.F_4.F_2; C_3 = F_6.F_7.F_2. \quad (3)$$

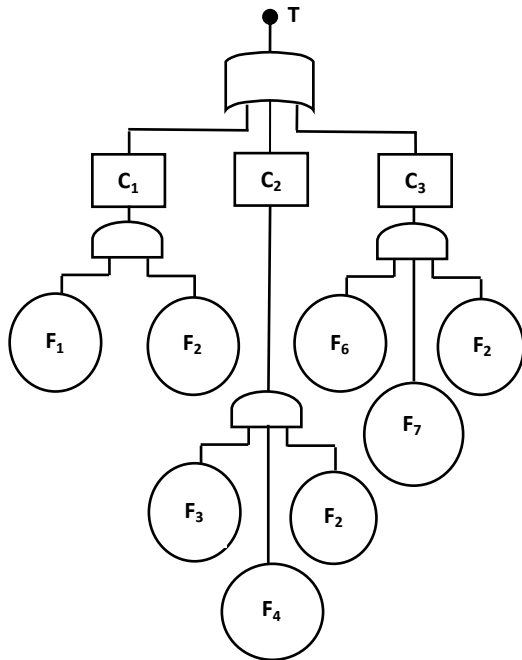


Fig. 4 – FTA of the system of Fig.3

Substituting in expression (2), we obtain:

$$F_S = \Pr(T) = \Pr(F_1.F_2) + \Pr(F_3.F_4.F_2) + \Pr(F_6.F_7.F_2) - \Pr(F_1.F_2.F_3.F_4.F_2.F_6.F_7.F_2), \text{ ou seja:}$$

$$F_S = \Pr(T) = \Pr(F_1.F_2) + \Pr(F_3.F_4.F_2) + \Pr(F_6.F_7.F_2) - \Pr(F_1.F_2.F_3.F_4.F_6.F_7) \quad (3)$$

Notice that in (3)  $F_2$  appears only once in the subtrahend. In fact, according to the idempotent

property of Boolean Algebra,  $F_2 \cap F_2 \cap F_2 \cap \dots = F_2.F_2.F_2 \dots = F_2$ .

To simplify the operations of expression (3), we consider that the time is small, something like  $t = 1h$ , the same way we did in the previous example. Thus, we have the expression  $F = \lambda$ .

Therefore, the expression (3) is as follows:

$$F_S = (\lambda_1. \lambda_2 + \lambda_3. \lambda_4. \lambda_2 + \lambda_6. \lambda_7. \lambda_2) - (\lambda_1. \lambda_2. \lambda_3. \lambda_4. \lambda_6. \lambda_7)$$

Additionally, suppose that  $\lambda_1 = 10^{-3}$ ,  $\lambda_2 = \lambda_3 = 2 \times 10^{-3}$ ,  $\lambda_4 = 10^{-4}$ , e  $\lambda_6 = \lambda_7 = 10^{-2}$ .

The addition of the first three terms give us the value  $2.2 \times 10^{-6}$ , and the subtrahend,  $4 \times 10^{-16}$ , meaning in this context that the subtrahend is almost "0". Therefore, we can affirm that

$$F_S = 2.2 \times 10^{-6}$$

Given that  $R + F = 1$ , we can write  $R_S = 1 - F_S = 1 - 2.2 \times 10^{-6} = 1 - 0.0000022 \therefore$

$$\therefore R_S = 0.999$$

Finally, it is important to note that the subtrahend in equation (2) is generally very small, allowing us, often, only consider parts of the sum, in this case  $\Pr(C_1) + \Pr(C_2) + \Pr(C_3)$ .

Thank you very much

References:

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3. Shooman, M.L., Probabilistic Reliability: An Engineering Approach, 2a. Ed., Kreiger, 1990, Melbourne.